

Notice of References Cited

Application/Control No.

09/372,879

Applicant(s)/Patent Under
Reexamination
SIDIROPOULOS ET AL.

Examiner

Dana Farahani

Art Unit

2814

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP-60000769-A	01-1985	JPO	SAKAI et al.	
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	P					
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